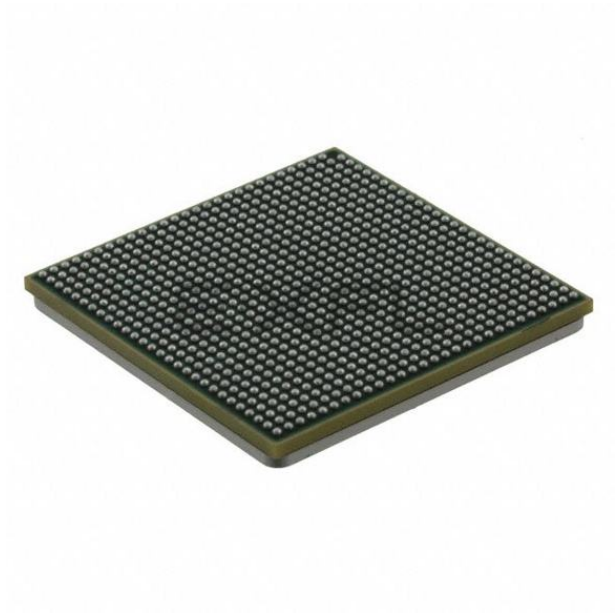

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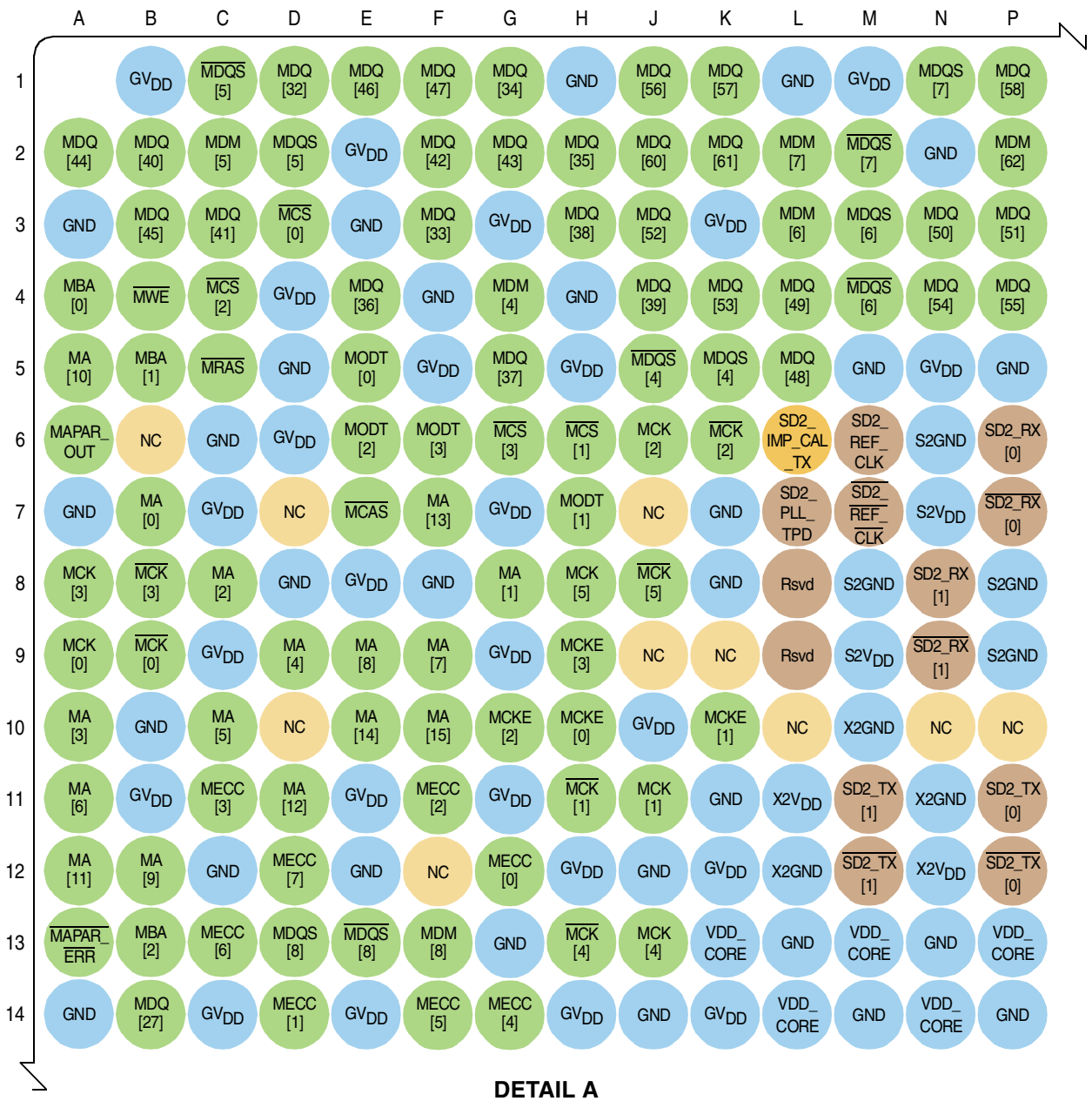
Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.25GHz
Co-Processors/DSP	-
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	SATA 3Gbps (1)
USB	USB 2.0 (2)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	-
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCPBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/ppc8535cvtath



DETAIL A

Figure 3. Chip Pin Map Detail A

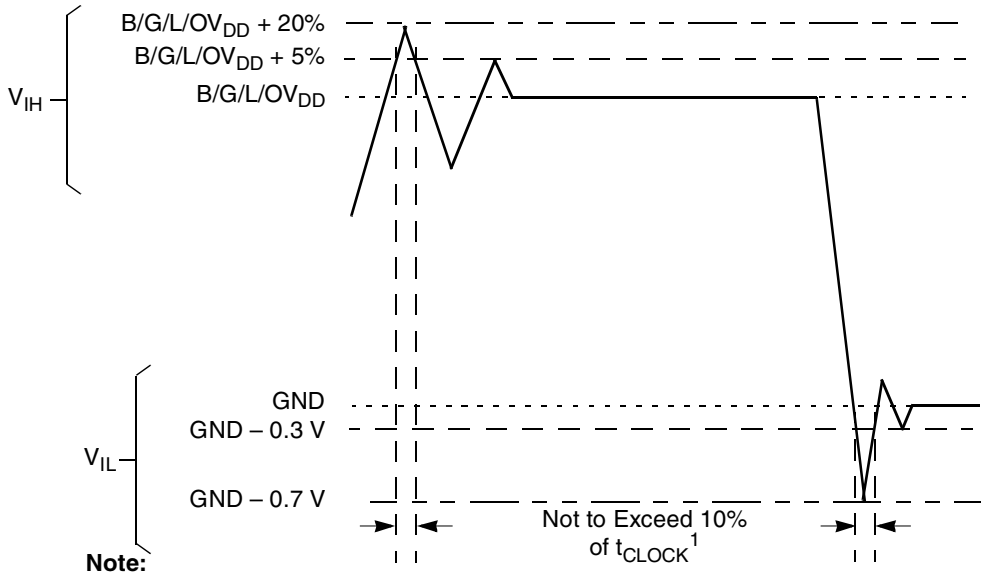
Table 1. Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
LAD[0:31]	Muxed data / address	K22,L21,L22,K23,K24, L24,L25,K25,L28,L27, K28,K27,J28,H28,H27, G27,G26,F28,F26,F25, E28,E27,E26,F24,E24, C26,G24,E23,G23,F22, G22,G21	I/O	BV_{DD}	5,9,29
LDP[0:3]	Data parity	K26,G28,B27,E25	I/O	BV_{DD}	29
LA[27]	Burst address	L19	O	BV_{DD}	5,9,29
LA[28:31]	Port address	K16,K17,H17,G17	O	BV_{DD}	5,7,9,29
$\overline{\text{LCS}}$[0:4]	Chip selects	K18,G19,H19,H20,G16	O	BV_{DD}	29
$\overline{\text{LCS5}}$/$\overline{\text{DMA\_DREQ2}}$	Chips selects / DMA Request	H16	I/O	BV_{DD}	1,29
$\overline{\text{LCS6}}$/$\overline{\text{DMA\_DACK2}}$	Chips selects / DMA Ack	J16	O	BV_{DD}	1,29
$\overline{\text{LCS7}}$/$\overline{\text{DMA\_DDONE2}}$	Chips selects / DMA Done	L18	O	BV_{DD}	1,29
$\overline{\text{LWE0}}$/$\overline{\text{LBS0}}$/$\overline{\text{LFWE}}$	Write enable / Byte select	J22	O	BV_{DD}	5,9,29
$\overline{\text{LWE[1:3]}}$/$\overline{\text{LBS[1:3]}}$	Write enable / Byte select	H22,H23,H21	O	BV_{DD}	5,9,29
LBCTL	Buffer control	J25	O	BV_{DD}	5,8,9,29
LALE	Address latch enable	J26	O	BV_{DD}	5,8,9,29
LGPL0/LFCLE	UPM general purpose line 0 / FLash command latch enable	J20	O	BV_{DD}	5,9,29
LGPL1/LFALE	UPM general purpose line 1 / Flash address latch enable	K20	O	BV_{DD}	5,9,29
LGPL2/$\overline{\text{LOE}}$/$\overline{\text{LFRE}}$	UPM general purpose line 2 / Output enable/Flash read enable	G20	O	BV_{DD}	5,8,9,29
LGPL3/$\overline{\text{LFWP}}$	UPM general purpose line 3 / Flash write protect	H18	O	BV_{DD}	5,9,29
LGPL4/$\overline{\text{LGTA}}$/LUPWAIT /LPBSE/LFRB	UPM general purpose line 4 / Target Ack/Wait/SDRAM parity byte select/Flash Ready-busy	L20	I/O	BV_{DD}	29, 35
LGPL5	UPM general purpose line 5 / Amux	K19	O	BV_{DD}	5,9,29
LCLK[0:2]	Local bus clock	H24,J24,H25	O	BV_{DD}	29
LSYNC_IN	Synchronization	D27	I	BV_{DD}	29
LSYNC_OUT	Local bus DLL	D28	O	BV_{DD}	29
DMA					
$\overline{\text{DMA\_DACK}}$[0:1] /GPIO[10:11]	DMA Acknowledge	AD6,AE10	O	OV_{DD}	—

Table 1. Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
XVDD	SerDes 1 transceiver supply	M21,N23,P20,R22,T20, U23,V21,W22,Y20, AA23	—	XV_{DD}	—
S2VDD	SerDes 2 core logic supply	R6,N7,M9	—	$S2V_{DD}$	—
X2VDD	SerDes 2 transceiver supply	R11,N12,L11	—	$X2V_{DD}$	—
VDD_CORE	Core, L2 logic supply	P13,U16,L16,M15,N14, R14,P15,N16,M13, U14,T13,L14,T15,R16, K13	—	V_{DD_CORE}	—
VDD_PLAT	Platform logic supply	T19,T17,V17,U18,R18, N18,M19,P19,P17,M17	—	V_{DD_PLAT}	—
AVDD_CORE	CPU PLL supply	AH16	—	AV_{DD_CORE}	20,28
AVDD_PLAT	Platform PLL supply	AH18	—	AV_{DD_PLAT}	20
AVDD_DDR	DDR PLL supply	AH19	—	AV_{DD_DDR}	20
AVDD_LBIU	Local Bus PLL supply	C28	—	AV_{DD_LBIU}	20
AVDD_PCI1	PCI PLL supply	AH20	—	AV_{DD_PCI1}	20
AVDD_SRDS	SerDes 1 PLL supply	W28	—	AV_{DD_SRDS}	20
AVDD_SRDS2	SerDes 2 PLL supply	T1	—	AV_{DD_SRDS2}	20
SENSEVDD_CORE	—	V15	—	V_{DD_CORE}	13
SENSEVDD_PLAT	—	W17	—	V_{DD_PLAT}	13
GND	Ground	D5,AE7,F4,D26,D23, C12,C15,E20,D8,B10, AF3,E3,J14,K21,F8,A3, F16,E12,E15,D17,L1, F21,H1,G13,G15,G18, C6,A14,A7,G25,H4, C20,J12,J15,J17,F27, M5,J27,K11,L26,K7, K8,T14,V14,M16,M18, P14,N15,N17,N19,N2, P5,P16,P18,M14,R15, R17,R19,T16,T18,L17, U15,U17,U19,V18,C27, Y13,AE26,AA19,AE21, B28,AC11,AD19,AD23, L15,AD15,AG23,AE9, A27,V7,Y7,AC5,U4,Y4, AE12,AB9,AA14,N13, R13,L13	—	—	—
XGND	SerDes 1Transceiver pad GND (xpadvss)	M20,M24,N22,P21, R23,T21,U22,V20, W23, Y21	—	—	—

This figure shows the undershoot and overshoot voltages at the interfaces of the chip.



Note:

1. t_{CLOCK} refers to the clock period associated with the respective interface:
   For I^2C and JTAG, t_{CLOCK} references SYSCLK.
   For DDR, t_{CLOCK} references MCLK.
   For eTSEC, t_{CLOCK} references EC_GTX_CLK125.
   For eLBC, t_{CLOCK} references LCLK.
   For PCI, t_{CLOCK} references PCI1_CLK or SYSCLK.

2. With the PCI overshoot allowed (as specified above), the device does not fully comply with the maximum AC ratings and device protection guideline outlined in the PCI rev. 2.2 standard (section 4.2.2.3).

Figure 7. Overshoot/Undershoot Voltage for $GV_{DD}/OV_{DD}/LV_{DD}$

The core voltage must always be provided at nominal 1.0 V . (See Table 3 for actual recommended core voltage). Voltage to the processor interface I/Os are provided through separate sets of supply pins and must be provided at the voltages shown in Table 3. The input voltage threshold scales with respect to the associated I/O supply voltage. OV_{DD} and LV_{DD} based receivers are simple CMOS I/O circuits and satisfy appropriate LVCMOS type specifications. The DDR2 and DDR3 SDRAM interface uses differential receivers referenced by the externally supplied MVREF*n* signal (nominally set to GVDD/2) as is appropriate for the SSTL_1.8 electrical signaling standard for DDR2 or 1.5-V electrical signaling for DDR3. The DDR DQS receivers cannot be operated in single-ended fashion. The complement signal must be properly driven and cannot be grounded.

Table 19. DDR SDRAM Output AC Timing Specifications (continued)

At recommended operating conditions with GV_{DD} of 1.8 V ± 5% for DDR2 or 1.5 V ± 5% for DDR3.

Parameter	Symbol [1]	Min	Max	Unit	Notes
<= 667 MHz		$0.9 \times t_{MCK}$			7
MDQS epilogue end	t_{DDKHME}			ns	6
<= 667 MHz		$0.4 \times t_{MCK}$	$0.6 \times t_{MCK}$		7

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (AX or DX). For example, t_{DDKHAS} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes from the high (H) state until outputs (A) are setup (S) or output valid time. Also, t_{DDKLDX} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.
2. All MCK/$\overline{\text{MCK}}$ referenced measurements are made from the crossing of the two signals ±0.1 V.
3. ADDR/CMD includes all DDR SDRAM output signals except MCK/$\overline{\text{MCK}}$, $\overline{\text{MCS}}$, and MDQ/MECC/MDM/MDQS.
4. Note that t_{DDKHMH} follows the symbol conventions described in note 1. For example, t_{DDKHMH} describes the DDR timing (DD) from the rising edge of the MCK[n] clock (KH) until the MDQS signal is valid (MH). t_{DDKHMH} can be modified through control of the DQSS override bits in the TIMING_CFG_2 register. This will typically be set to the same delay as the clock adjust in the CLK_CNTL register. The timing parameters listed in the table assume that these 2 parameters have been set to the same adjustment value. See the *MPC8536E PowerQUICC III Integrated Processor Reference Manual* for a description and understanding of the timing modifications enabled by use of these bits.
5. Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), ECC (MECC), or data mask (MDM). The data strobe should be centered inside of the data eye at the pins of the microprocessor.
6. All outputs are referenced to the rising edge of MCK[n] at the pins of the microprocessor. Note that t_{DDKHMP} follows the symbol conventions described in note 1.
7. Maximum DDR2 and DDR3 frequency is 667 MHz

NOTE

For the ADDR/CMD setup and hold specifications in Table 19, it is assumed that the Clock Control register is set to adjust the memory clocks by 1/2 applied cycle.

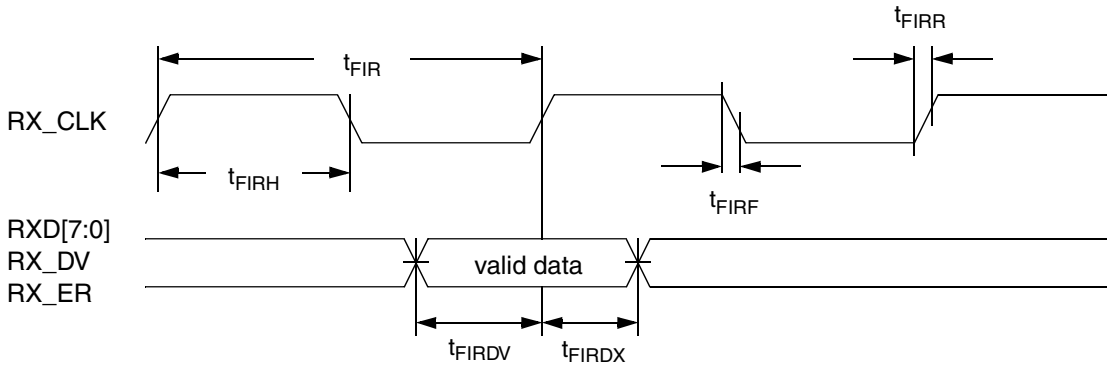


Figure 15. FIFO Receive AC Timing Diagram

2.9.2.2 GMII AC Timing Specifications

This section describes the GMII transmit and receive AC timing specifications.

2.9.2.2.1 GMII Transmit AC Timing Specifications

This table provides the GMII transmit AC timing specifications.

Table 28. GMII Transmit AC Timing Specifications

At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
GTX_CLK clock period	t_{GTK}	—	8.0	—	ns
GTX_CLK to GMII data TXD[7:0], TX_ER, TX_EN delay	t_{GTKHDX}[3]	0.5	—	5.0	ns
GTX_CLK data clock rise time (20%-80%)	t_{GTXR}	—	—	1.0	ns
GTX_CLK data clock fall time (80%-20%)	t_{GTXF}	—	—	1.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{GTKHDV} symbolizes GMII transmit timing (GT) with respect to the t_{GTX} clock reference (K) going to the high state (H) relative to the time date input signals (D) reaching the valid state (V) to state or setup time. Also, t_{GTKHDX} symbolizes GMII transmit timing (GT) with respect to the t_{GTX} clock reference (K) going to the high state (H) relative to the time date input signals (D) going invalid (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GTX} represents the GMII(G) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Data valid t_{GTKHDV} to GTX_CLK Min Setup time is a function of clock period and max hold time. (Min Setup = Cycle time - Max Hold)

This figure shows the GMII transmit AC timing diagram.

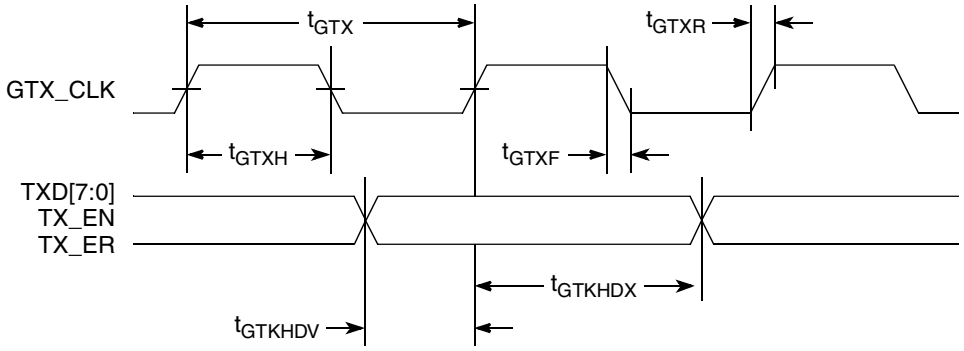


Figure 16. GMII Transmit AC Timing Diagram

2.9.2.2.2 GMII Receive AC Timing Specifications

This table provides the GMII receive AC timing specifications.

Table 29. GMII Receive AC Timing Specifications

At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
RX_CLK clock period	t_{GRX}	—	8.0	—	ns
RX_CLK duty cycle	t_{GRXH}/t_{GRX}	35	—	65	%
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t_{GRDVKH}	2.0	—	—	ns
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t_{GRDXKH}	0	—	—	ns
RX_CLK clock rise (20%-80%)	t_{GRXR}	—	—	1.0	ns
RX_CLK clock fall time (80%-20%)	t_{GRXF}	—	—	1.0	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{GRDVKH} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{RX} clock reference (K) going to the high state (H) or setup time. Also, t_{GRDXKL} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{GRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GRX} represents the GMII (G) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

This figure provides the AC test load for eTSEC.

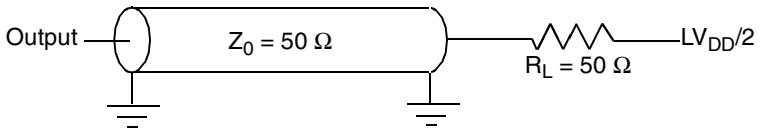


Figure 17. eTSEC AC Test Load

This figure shows the GMII receive AC timing diagram.

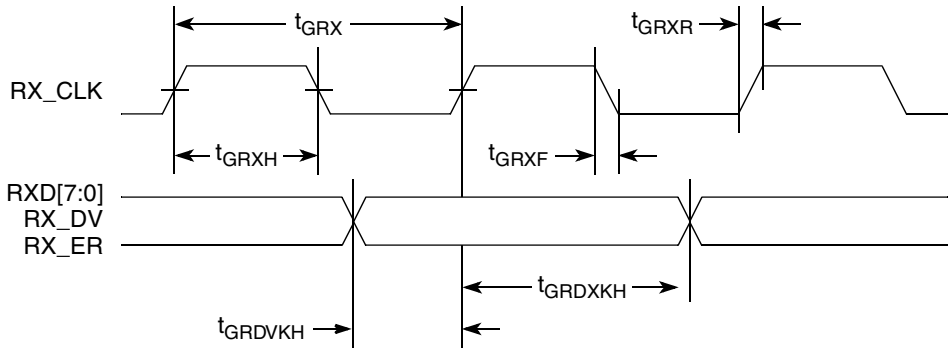


Figure 18. GMII Receive AC Timing Diagram

2.9.2.3 MII AC Timing Specifications

This section describes the MII transmit and receive AC timing specifications.

2.9.2.3.1 MII Transmit AC Timing Specifications

This table provides the MII transmit AC timing specifications.

Table 30. MII Transmit AC Timing Specifications

At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
TX_CLK clock period 10 Mbps	t_{MTX}	—	400	—	ns
TX_CLK clock period 100 Mbps	t_{MTX}	—	40	—	ns
TX_CLK duty cycle	t_{MTXH}/t_{MTX}	35	—	65	%
TX_CLK to MII data TXD[3:0], TX_ER, TX_EN delay	t_{MTKHDX}	1	5	15	ns
TX_CLK data clock rise (20%-80%)	t_{MTXR}	1.0	—	4.0	ns
TX_CLK data clock fall (80%-20%)	t_{MTXF}	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

2.10.1 MII Management DC Electrical Characteristics

The EC_MDC and EC_MDIO are defined to operate at a supply voltage of 3.3 V. The DC electrical characteristics for EC_MDIO and EC_MDC are provided in the following table.

Table 44. MII Management DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
Supply voltage (3.3 V)	OV_{DD}	3.13	3.47	V
Output high voltage (OV_{DD} = Min, I_{OH} = –4.0 mA)	V_{OH}	2.40	OV_{DD} + 0.3	V
Output low voltage (OV_{DD} =Min, I_{OL} = 4.0 mA)	V_{OL}	GND	0.40	V
Input high voltage	V_{IH}	2.0	—	V
Input low voltage	V_{IL}	—	0.90	V
Input high current (OV_{DD} = Max, V_{IN} [1] = 2.1 V)	I_{IH}	—	40	μA
Input low current (OV_{DD} = Max, V_{IN} = 0.5 V)	I_{IL}	–600	—	μA

Note:

1. Note that the symbol V_{IN}, in this case, represents the OV_{IN} symbol referenced in Table 1 and Table 2.

2.10.2 MII Management AC Electrical Specifications

This table provides the MII management AC timing specifications.

Table 45. MII Management AC Timing Specifications

At recommended operating conditions with OVDD is 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit	Notes
EC_MDC frequency	f_{MDC}	0.74	2.5	8.3	MHz	2
EC_MDC period	t_{MDC}	120	400	1350	ns	—
EC_MDC clock pulse width high	t_{MDCH}	32	—	—	ns	—
EC_MDC to EC_MDIO delay	t_{MDKHDX}	(16 * t_{plb_clk})-3	—	(16 * t_{plb_clk})+3	ns	3,5,6
EC_MDIO to EC_MDC setup time	t_{MDDVKH}	5	—	—	ns	—

Table 54. Local Bus General Timing Parameters—PLL Bypassed (continued)

Parameter	Symbol [1]	Min	Max	Unit	Notes
Local bus clock to data valid for LAD/LDP	$t_{LBKLOV2}$	—	0.5	ns	4
Local bus clock to address valid for LAD, and LALE	$t_{LBKLOV3}$	—	0.5	ns	4
Local bus clock to LALE assertion	$t_{LBKLOV4}$	—	0.5	ns	4
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKLOX1}$	—	2.2	ns	4,8
Output hold from local bus clock for LAD/LDP	$t_{LBKLOX2}$	—	2.2	ns	4,8
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKLOZ1}$	—	0.1	ns	7
Local bus clock to output high impedance for LAD/LDP	$t_{LBKLOZ2}$	—	0.1	ns	7

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(First two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(First two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to local bus clock for PLL bypass mode.
3. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
4. All signals are measured from BVDD/2 of the rising edge of local bus clock for PLL bypass mode to 0.4 x BVDD of the signal in question for 3.3-V signaling levels.
5. Input timings are measured at the pin.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is guaranteed with LBCR[AHD] = 0.
7. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
8. These timing parameters for PLL bypass mode are defined in the opposite direction of the PLL enabled output hold timing parameters.

Table 55. eSDHC interface DC Electrical Characteristics (continued)

At recommended operating conditions (see Table 3)

Characteristic	Symbol	Condition	Min	Max	Unit	Notes
Output low voltage	V_{OL}	I_{OL} = 100uA @OVDDmin	—	0.125 * OVDD	V	—
Output high voltage	V_{OH}	I_{OH} = -100 uA	OV_{DD} - 0.2	—	—	2
Output low voltage	V_{OL}	I_{OL} = 2 mA	—	0.3	—	2

Notes:

1. The min V_{IL} and V_{IH} values are based on the respective min and max OV_{IN} values found in Table 3.
2. Open drain mode for MMC cards only.

2.13.2 eSDHC AC Timing Specifications

This table provides the eSDHC AC timing specifications as defined in the following figure.

Table 56. eSDHC AC Timing Specifications

At recommended operating conditions (see Table 3)

Parameter	Symbol[1]	Min	Max	Unit	Notes
SD_CLK clock frequency: SD/SDIO Full speed/high speed mode MMC Full speed/high speed mode	f_{SHSCK}	 0	 25/50 20/52	MHz	2, 5
SD_CLK clock frequency - identification mode	f_{SIDCK}	0 100	400	KHz	3, 5
SD_CLK clock low time - High speed/Full speed mode	t_{SHSCKL}	7/10	—	ns	5
SD_CLK clock high time - High speed/Full speed mode	t_{SHSCKH}	7/10	—	ns	5
SD_CLK clock rise and fall times	t_{SHSCKR}/ t_{SHSCKF}	—	3	ns	5
Input setup times: SD_CMD, SD_DATx, SD_CD to SD_CLK	$t_{SHSIVKH}$	2.5	—	ns	4,5,6
Input hold times: SD_CMD, SD_DATx, SD_CD to SD_CLK	$t_{SHSIXKH}$	2.5	—	ns	5,6
Output delay time: SD_CLK to SD_CMD, SD_DATx valid	$t_{SHSKHOV}$	–3	3	ns	5,6

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first three letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first three letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{FHSKHOV}$ symbolizes eSDHC high speed mode device timing (SHS) clock reference (K) going to the high (H) state, with respect to the output (O) reaching the invalid state (X) or output hold time. Note that, in general, the clock reference symbol representation is based on five letters representing the clock of a particular functional. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. In full speed mode, clock frequency value can be 0–25 MHz for a SD/SDIO card and 0–20 MHz for a MMC card. In high speed mode, clock frequency value can be 0–50 MHz for a SD/SDIO card and 0–52MHz for a MMC card.
3. 0 Hz means to stop the clock. The given minimum frequency range is for cases were a continuous clock is required.
4. To satisfy setup timing, one way board routing delay between Host and Card, on SD_CLK, SD_CMD and SD_DATx should not exceed 1 ns.
5. $C_{CARD} \leq 10$ pF, (1 card), and $C_L = C_{BUS} + C_{HOST} + C_{CARD} \leq 40$ pF
6. The parameter values apply to both full speed and high speed modes.

This figure provides the eSDHC clock input timing diagram.

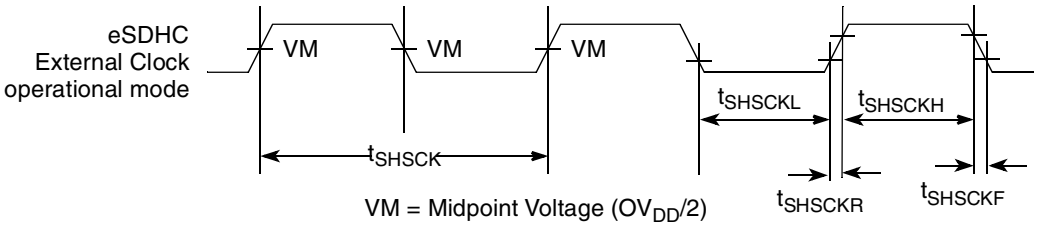


Figure 43. eSDHC Clock Input Timing Diagram

This figure provides the data and command input/output timing diagram.

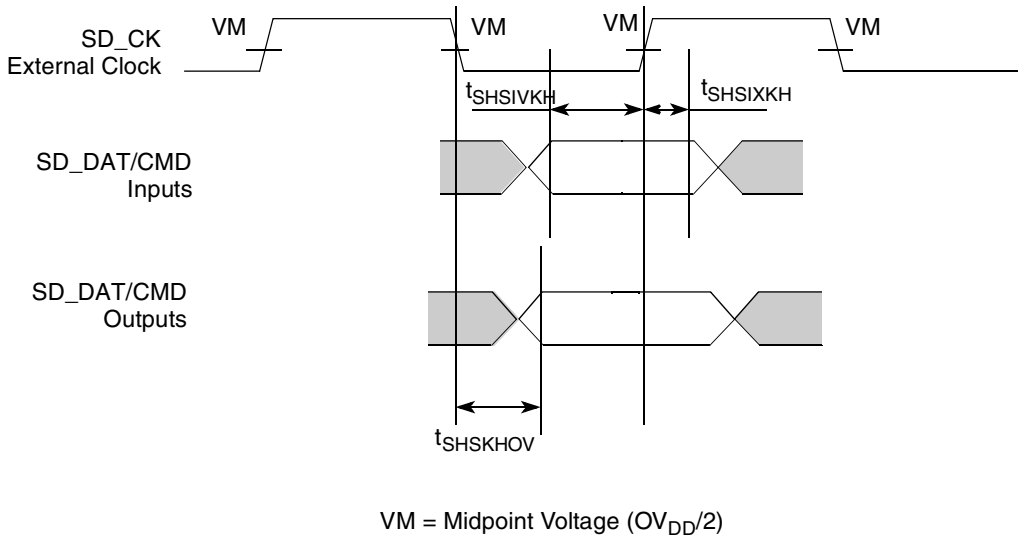


Figure 44. eSDHC Data and Command Input/Output Timing Diagram Referenced to Clock

2.14 Programmable Interrupt Controller (PIC)

In IRQ edge trigger mode, when an external interrupt signal is asserted (according to the programmed polarity), it must remain the assertion for at least 3 system clocks (SYSCLK periods).

2.15 JTAG

This section describes the DC and AC electrical specifications for the IEEE 1149.1 (JTAG) interface of the chip.

2.15.1 JTAG DC Electrical Characteristics

This table provides the DC electrical characteristics for the JTAG interface.

Table 57. JTAG DC Electrical Characteristics

Parameter	Symbol [1]	Min	Max	Unit
High-level input voltage	V_{IH}	2	OV_{DD} + 0.3	V
Low-level input voltage	V_{IL}	-0.3	0.8	V

Table 57. JTAG DC Electrical Characteristics (continued)

Parameter	Symbol [1]	Min	Max	Unit
Input current (V_{IN}[1] = 0 V or V_{IN} = V_{DD})	I_{IN}	—	±5	μA
High-level output voltage (OV_{DD} = min, I_{OH} = -2 mA)	V_{OH}	2.4	—	V
Low-level output voltage (OV_{DD} = min, I_{OL} = 2 mA)	V_{OL}	—	0.4	V

Notes:
1. Note that the symbol V_{IN}, in this case, represents the OV_{IN}.

2.15.2 JTAG AC Electrical Specifications

This section describes the AC electrical specifications for the IEEE 1149.1 (JTAG) interface of the chip.

This table provides the JTAG AC timing specifications as defined in the following figures.

Table 58. JTAG AC Timing Specifications (Independent of SYSCLK)

At recommended operating conditions (see Table 3).

Parameter	Symbol [1]	Min	Max	Unit	Notes
JTAG external clock frequency of operation	f_{JTG}	0	33.3	MHz	—
JTAG external clock cycle time	t_{JTG}	30	—	ns	—
JTAG external clock pulse width measured at 1.4 V	t_{JTKHKL}	15	—	ns	—
JTAG external clock rise and fall times	t_{JTGR} & t_{JTGF}	0	2	ns	—
$\overline{TRST}$ assert time	t_{TRST}	25	—	ns	2
Input setup times:	t_{JTDVKH}	4	—	ns	
Input hold times:	t_{JTDXKH}	10	—	ns	
Output Valid times:	t_{JTKLDV}	—	10	ns	3
Output hold times:	t_{JTKLDX}	0	—	ns	3

Notes:
1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{JTDVKH} symbolizes JTAG device timing (JT) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{JTG} clock reference (K) going to the high (H) state or setup time. Also, t_{JTDXKH} symbolizes JTAG timing (JT) with respect to the time data input signals (D) went invalid (X) relative to the t_{JTG} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. $\overline{TRST}$ is an asynchronous level sensitive signal. The setup time is for test purposes only.
3.) The output timings are measured at the pins. All output timings assume a purely resistive 50-Ω load. Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.

Table 61. Differential Receiver (RX) Input Characteristics (continued)

Parameter	Symbol	Min	Typical	Max	Units	Notes
RX Differential Mode Return loss 150 MHz - 300 MHz 300 MHz - 600 MHz 600 MHz - 1.2 GHz 1.2 GHz - 2.4 GHz 2.4 GHz - 3.0 GHz 3.0 GHz - 5.0 GHz	RL_{SATA_RXDD11}	 — — — — — —	 — — — — — —	 18 14 10 8 3 1	 dB	2, 3
RX Common Mode Return loss 150 MHz - 300 MHz 300 MHz - 600 MHz 600 MHz - 1.2 GHz 1.2 GHz - 2.4 GHz 2.4 GHz - 3.0 GHz 3.0 GHz - 5.0 GHz	RL_{SATA_RXCC11}	 — — — — — —	 — — — — — —	 5 5 2 2 2 1	 dB	2, 3, 4
RX Impedance Balance 150 MHz - 300 MHz 300 MHz - 600 MHz 600 MHz - 1.2 GHz 1.2 GHz - 2.4 GHz 2.4 GHz - 3.0 GHz 3.0 GHz - 5.0 GHz	RL_{SATA_RXDC11}	 — — — — — —	 — — — — — —	 30 30 20 10 4 4	 dB	2, 3
Deterministic jitter 1.5G 3.0G	U_{SATA_RXDJ}	—	—	 0.4 0.47	 UI	—
Total Jitter 1.5G 3.0G	U_{SATA_RXTJ}	—	—	 0.65 0.65	 UI	—

Notes:
1. The min values apply only to Gen1m, and Gen2m. the min values for Gen1i is 325 mVp-p and for Gen2i is 275 mVp-p.
2. Only applies when operating in 3.0Gb data rate mode.
3. The max value stated for 3.0 GHz - 5.0 GHz range only applies to Gen2i mode and not to Gen2m mode.
4. The max value stated for 2.4 GHz - 3.0 GHz range only applies to Gen2i mode for Gen2m the value is 1.
5. Only applies to Gen1i mode.

This figure shows the PCI output AC timing conditions.

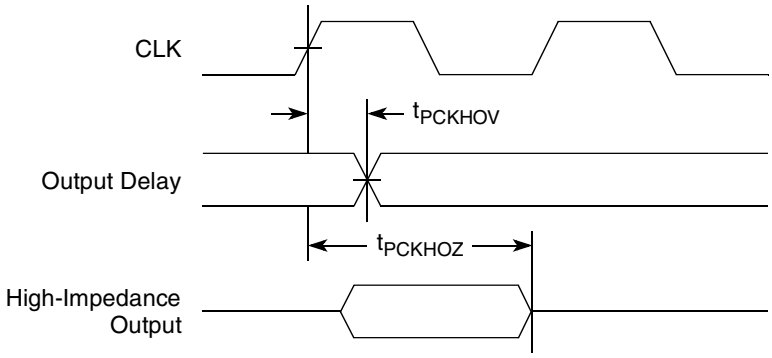


Figure 56. PCI Output AC Timing Measurement Condition

2.20 High-Speed Serial Interfaces

This chip features two Serializer/Deserializer (SerDes) interfaces to be used for high-speed serial interconnect applications. The SerDes1 interface is dedicated for PCI Express data transfers. The SerDes2 can be used for SGMII or SATA.

This section describes the common portion of SerDes DC electrical specifications, which is the DC requirement for SerDes Reference Clocks. The SerDes data lane's transmitter and receiver reference circuits are also shown.

2.20.1 Signal Terms Definition

The SerDes utilizes differential signaling to transfer data across the serial link. This section defines terms used in the description and specification of differential signals.

Figure 57 shows how the signals are defined. For illustration purposes, only one SerDes lane is used for description. The figure shows waveform for either a transmitter output (SDn_TX and $\overline{\text{SDn\_TX}}$) or a receiver input (SDn_RX and $\overline{\text{SDn\_RX}}$). Each signal swings between A Volts and B Volts where A > B.

Using this waveform, the definitions are as follows. To simplify illustration, the following definitions assume that the SerDes transmitter and receiver operate in a fully symmetrical differential signaling environment.

1. **Single-Ended Swing**

The transmitter output signals and the receiver input signals SDn_TX, $\overline{\text{SDn\_TX}}$, SDn_RX and $\overline{\text{SDn\_RX}}$ each have a peak-to-peak swing of A - B Volts. This is also referred as each signal wire's Single-Ended Swing.

2. **Differential Output Voltage, V_{OD}** (or **Differential Output Swing**):

The Differential Output Voltage (or Swing) of the transmitter, V_{OD}, is defined as the difference of the two complimentary output voltages: V_{SDn_TX} - $V_{\overline{SDn\_TX}}$. The V_{OD} value can be either positive or negative.

3. **Differential Input Voltage, V_{ID}** (or **Differential Input Swing**):

The Differential Input Voltage (or Swing) of the receiver, V_{ID}, is defined as the difference of the two complimentary input voltages: V_{SDn_RX} - $V_{\overline{SDn\_RX}}$. The V_{ID} value can be either positive or negative.

4. **Differential Peak Voltage, V_{DIFFp}**

The peak value of the differential transmitter output signal or the differential receiver input signal is defined as Differential Peak Voltage, V_{DIFFp} = |A - B| Volts.

5. **Differential Peak-to-Peak, $V_{DIFFp-p}$**

Since the differential output signal of the transmitter and the differential input signal of the receiver each range from A - B to -(A - B) Volts, the peak-to-peak value of the differential transmitter output signal or the differential receiver input signal is defined as Differential Peak-to-Peak Voltage, $V_{DIFFp-p} = 2*V_{DIFFp} = 2 * |(A - B)|$ Volts, which is twice of differential swing in amplitude, or twice of the differential

Table 71. Differential Transmitter (TX) Output Specifications (continued)

Symbol	Parameter	Min	Nom	Max	Units	Comments
$T_{TX-IDLE-SET-TO-IDLE}$	Maximum time to transition to a valid electrical idle after sending an electrical Idle ordered set	—	—	20	UI	After sending an Electrical Idle ordered set, the Transmitter must meet all Electrical Idle Specifications within this time. This is considered a debounce time for the Transmitter to meet Electrical Idle after transitioning from L0.
$T_{TX-IDLE-TO-DIFF-DATA}$	Maximum time to transition to valid TX specifications after leaving an electrical idle condition	—	—	20	UI	Maximum time to meet all TX specifications when transitioning from Electrical Idle to sending differential data. This is considered a debounce time for the TX to meet all TX specifications after leaving Electrical Idle
$RL_{TX-DIFF}$	Differential Return Loss	12	—	—	dB	Measured over 50 MHz to 1.25 GHz. See Note 4
RL_{TX-CM}	Common Mode Return Loss	6	—	—	dB	Measured over 50 MHz to 1.25 GHz. See Note 4
$Z_{TX-DIFF-DC}$	DC Differential TX Impedance	80	100	120	Ω	TX DC Differential mode Low Impedance
Z_{TX-DC}	Transmitter DC Impedance	40	—	—	Ω	Required TX D+ as well as D- DC Impedance during all states
$L_{TX-SKEW}$	Lane-to-Lane Output Skew	—	—	500 + 2 UI	ps	Static skew between any two Transmitter Lanes within a single Link
C_{TX}	AC Coupling Capacitor	75	—	200	nF	All Transmitters shall be AC coupled. The AC coupling is required either within the media or within the transmitting component itself. See Note 8.
$T_{crosslink}$	Crosslink Random Timeout	0	—	1	ms	This random timeout helps resolve conflicts in crosslink configuration by eventually resulting in only one Downstream and one Upstream Port. See Note 7.

Notes:

1. No test load is necessarily associated with this value.
2. Specified at the measurement point into a timing and voltage compliance test load as shown in Figure 52 and measured over any 250 consecutive TX UIs. (Also refer to the transmitter compliance eye diagram shown in Figure 50)
3. A T_{TX-EYE} = 0.70 UI provides for a total sum of deterministic and random jitter budget of $T_{TX-JITTER-MAX}$ = 0.30 UI for the Transmitter collected over any 250 consecutive TX UIs. The $T_{TX-EYE-MEDIAN-to-MAX-JITTER}$ median is less than half of the total TX jitter budget collected over any 250 consecutive TX UIs. It should be noted that the median is not the same as the mean. The jitter median describes the point in time where the number of jitter points on either side is approximately equal as opposed to the averaged time value.
4. The Transmitter input impedance shall result in a differential return loss greater than or equal to 12 dB and a common mode return loss greater than or equal to 6 dB over a frequency range of 50 MHz to 1.25 GHz. This input impedance requirement applies to all valid input levels. The reference impedance for return loss measurements is 50 ohms to ground for both the D+ and D- line (that is, as measured by a Vector Network Analyzer with 50 ohm probes—see Figure 52). Note that the series capacitors C_{TX} is optional for the return loss measurement.
5. Measured between 20-80% at transmitter package pins into a test load as shown in Figure 52 for both V_{TX-D+} and V_{TX-D-}.
6. See Section 4.3.1.8 of the PCI Express Base Specifications Rev 1.0a
7. See Section 4.2.6.3 of the PCI Express Base Specifications Rev 1.0a
8. SerDes transmitter does not have C_{TX} built-in. An external AC Coupling capacitor is required.

2.21.4.3 Differential Receiver (RX) Input Specifications

This table defines the specifications for the differential input at all receivers (RXs). The parameters are specified at the component pins.

Table 72. Differential Receiver (RX) Input Specifications

Symbol	Parameter	Min	Nom	Max	Units	Comments
UI	Unit Interval	399.88	400	400.12	ps	Each UI is 400 ps ± 300 ppm. UI does not account for Spread Spectrum Clock dictated variations. See Note 1.
$V_{RX-DIFFp-p}$	Differential Peak-to-Peak Output Voltage	0.175	—	1.200	V	$V_{RX-DIFFp-p} = 2*\|V_{RX-D+} - V_{RX-D-}\|$ See Note 2.
T_{RX-EYE}	Minimum Receiver Eye Width	0.4	—	—	UI	The maximum interconnect media and Transmitter jitter that can be tolerated by the Receiver can be derived as $T_{RX-MAX-JITTER} = 1 - T_{RX-EYE} = 0.6$ UI. See Notes 2 and 3.
$T_{RX-EYE-MEDIAN-to-MAX-JITTER}$	Maximum time between the jitter median and maximum deviation from the median.	—	—	0.3	UI	Jitter is defined as the measurement variation of the crossing points ($V_{RX-DIFFp-p}$ = 0 V) in relation to a recovered TX UI. A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. Jitter is measured using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI. See Notes 2, 3 and 7.
$V_{RX-CM-ACp}$	AC Peak Common Mode Input Voltage	—	—	150	mV	$V_{RX-CM-ACp} = \|V_{RXD+} - V_{RXD-}\|/2 + V_{RX-CM-DC}$ $V_{RX-CM-DC} = DC_{(avg)}$ of $\|V_{RX-D+} + V_{RX-D-}\|/2$ See Note 2
$RL_{RX-DIFF}$	Differential Return Loss	15	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D- lines biased at +300 mV and –300 mV, respectively. See Note 4
RL_{RX-CM}	Common Mode Return Loss	6	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D- lines biased at 0 V. See Note 4
$Z_{RX-DIFF-DC}$	DC Differential Input Impedance	80	100	120	Ω	RX DC Differential mode impedance. See Note 5
Z_{RX-DC}	DC Input Impedance	40	50	60	Ω	Required RX D+ as well as D- DC Impedance (50 ± 20% tolerance). See Notes 2 and 5.
$Z_{RX-HIGH-IMP-DC}$	Powered Down DC Input Impedance	200 k	—	—	Ω	Required RX D+ as well as D– DC Impedance when the Receiver terminations do not have power. See Note 6.
$V_{RX-IDLE-DET-DIFFp-p}$	Electrical Idle Detect Threshold	65	—	175	mV	$V_{RX-IDLE-DET-DIFFp-p} = 2*\|V_{RX-D+} - V_{RX-D-}\|$ Measured at the package pins of the Receiver
$T_{RX-IDLE-DET-DIFF-ENTERTIME}$	Unexpected Electrical Idle Enter Detect Threshold Integration Time	—	—	10	ms	An unexpected Electrical Idle ($V_{RX-DIFFp-p} < V_{RX-IDLE-DET-DIFFp-p}$) must be recognized no longer than $T_{RX-IDLE-DET-DIFF-ENTERING}$ to signal an unexpected idle condition.

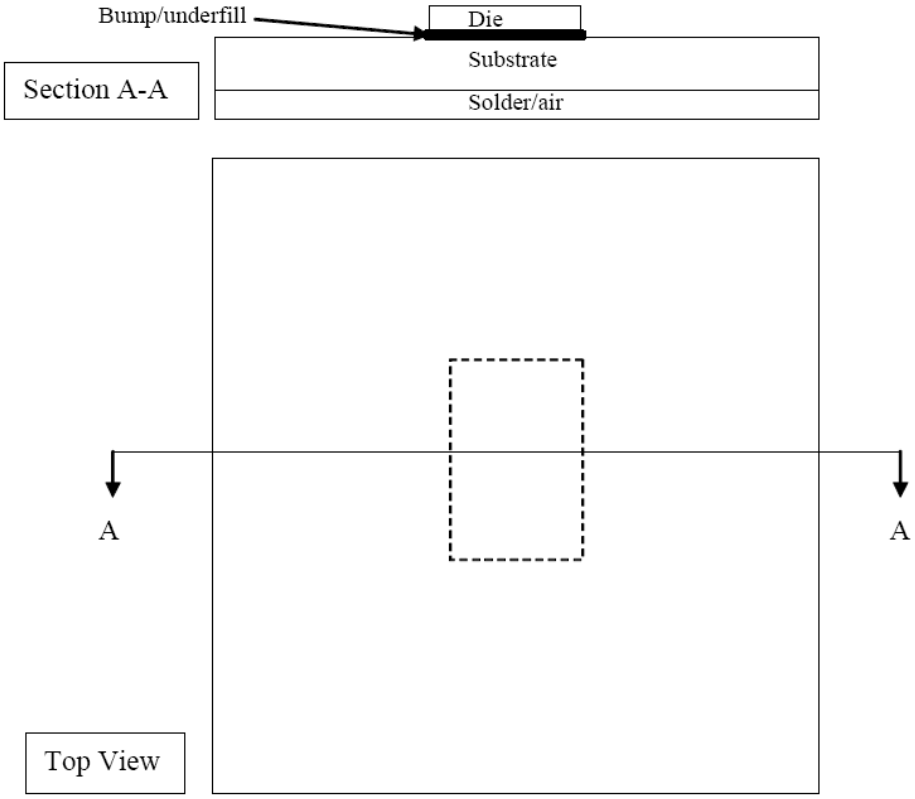


Figure 72. System-Level Thermal Model for the Chip (Not to Scale)

The Flotherm library files of the parts have a dense grid to accurately capture the laminar boundary layer for flow over the part in standard JEDEC environments, as well as the heat spreading in the board under the package. In a real system, however, the part will require a heat sink to be mounted on it. In this case, the predominant heat flow path will be from the die to the heat sink. Grid density lower than currently in the package library file will suffice for these simulations. The user will need to determine the optimal grid for their specific case.

2.24.3 Thermal Management Information

This section provides thermal management information for the flip chip plastic ball grid array (FC-PBGA) package for air-cooled applications. Proper thermal control design is primarily dependent on the system-level design—the heat sink, airflow, and thermal interface material.

These capacitors should have a value of 0.1 µF. Only ceramic SMT (surface mount technology) capacitors should be used to minimize lead inductance, preferably 0402 or 0603 sizes.

In addition, it is recommended that there be several bulk storage capacitors distributed around the PCB, feeding the V_{DD}, TV_{DD}, BV_{DD}, OV_{DD}, GV_{DD}, and LV_{DD} planes, to enable quick recharging of the smaller chip capacitors. These bulk capacitors should have a low ESR (equivalent series resistance) rating to ensure the quick response time necessary. They should also be connected to the power and ground planes through two vias to minimize inductance. Suggested bulk capacitors—100–330 µF (AVX TPS tantalum or Sanyo OSCON). However, customers should work directly with their power regulator vendor for best values types and quantity of bulk capacitors.

3.5 SerDes Block Power Supply Decoupling Recommendations

he SerDes1 and SerDes2 blocks require a clean, tightly regulated source of power (SnV_{DD} and XnV_{DD}) to ensure low jitter on transmit and reliable recovery of data in the receiver. An appropriate decoupling scheme is outlined below.

Only surface mount technology (SMT) capacitors should be used to minimize inductance. Connections from all capacitors to power and ground should be done with multiple vias to further reduce inductance.

- First, the board should have at least 10 x 10-nF SMT ceramic chip capacitors as close as possible to the supply balls of the chip. Where the board has blind vias, these capacitors should be placed directly below the chip supply and ground connections. Where the board does not have blind vias, these capacitors should be placed in a ring around the chip as close to the supply and ground connections as possible.
- Second, there should be a 1-µF ceramic chip capacitor from each SerDes supply (SnV_{DD} and XnV_{DD}) to the board ground plane on each side of the chip. This should be done for all SerDes supplies.
- Third, between the chip and any SerDes voltage regulator there should be a 10-µF, low equivalent series resistance (ESR) SMT tantalum chip capacitor and a 100-µF, low ESR SMT tantalum chip capacitor. This should be done for all SerDes supplies.

3.6 Connection Recommendations

To ensure reliable operation, it is highly recommended to connect unused inputs to an appropriate signal level. All unused active low inputs should be tied to $V_{DD,}TV_{DD}$, BV_{DD}, OV_{DD}, GV_{DD}, and LV_{DD} as required. All unused active high inputs should be connected to GND. All NC (no-connect) signals must remain unconnected. Power and ground connections must be made to all external $V_{DD,}TV_{DD}$, BV_{DD}, OV_{DD}, GV_{DD}, and LV_{DD} and GND pins of the chip.

3.7 Pull-Up and Pull-Down Resistor Requirements

The chip requires weak pull-up resistors (2–10 kΩ is recommended) on open drain type pins including I^2C pins and MPIC interrupt pins.

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in Figure 78. Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions as most have asynchronous behavior and spurious assertion will give unpredictable results.

The following pins must NOT be pulled down during power-on reset: TSEC1_TXD[3], $\overline{\text{HRESET\_REQ}}$, TRIG_OUT/READY/$\overline{\text{QUIESCE}}$, MSRCID[2:4], ASLEEP. The UART_SOUT[0:1] and $\overline{\text{TEST\_SEL}}$ pins must be set to a proper state during POR configuration. Please refer to the pinlist table (see Table 62) of the individual chip for more details.

See the PCI 2.2 specification for all pull-ups required for PCI.

3.8 Output Buffer DC Impedance

The chip drivers are characterized over process, voltage, and temperature. For all buses, the driver is a push-pull single-ended driver type (open drain for I^2C).

Careful board layout with stubless connections to these pull-down resistors coupled with the large value of the pull-down resistor should minimize the disruption of signal quality or speed for output pins thus configured.

The platform PLL ratio and e500 PLL ratio configuration pins are not equipped with these default pull-up devices.

3.10 JTAG Configuration Signals

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in Figure 78. Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions as most have asynchronous behavior and spurious assertion will give unpredicatable results.

Boundary-scan testing is enabled through the JTAG interface signals. The $\overline{\text{TRST}}$ signal is optional in the IEEE 1149.1 specification, but it is provided on all processors built on Power Architecture technology. The chip requires $\overline{\text{TRST}}$ to be asserted during power-on reset flow to ensure that the JTAG boundary logic does not interfere with normal chip operation. While the TAP controller can be forced to the reset state using only the TCK and TMS signals, generally systems assert $\overline{\text{TRST}}$ during the power-on reset flow. Simply tying $\overline{\text{TRST}}$ to $\overline{\text{HRESET}}$ is not practical because the JTAG interface is also used for accessing the common on-chip processor (COP), which implements the debug interface to the chip.

The COP function of these processors allow a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The COP interface connects primarily through the JTAG port of the processor, with some additional status monitoring signals. The COP port requires the ability to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$ in order to fully control the processor. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, then the COP reset signals must be merged into these signals with logic.

The arrangement shown in Figure 78 allows the COP port to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$, while ensuring that the target can drive $\overline{\text{HRESET}}$ as well.

The COP interface has a standard header, shown in Figure 79, for connection to the target system, and is based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header). The connector typically has pin 14 removed as a connector key.

The COP header adds many benefits such as breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features. An inexpensive option can be to leave the COP header unpopulated until needed.

There is no standardized way to number the COP header; consequently, many different pin numbers have been observed from emulator vendors. Some are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom, while still others number the pins counter clockwise from pin 1 (as with an IC). Regardless of the numbering, the signal placement recommended in Figure 79 is common to all known emulators.

3.10.1 Termination of Unused Signals

If the JTAG interface and COP header will not be used, Freescale recommends the following connections:

- $\overline{\text{TRST}}$ should be tied to $\overline{\text{HRESET}}$ through a 0 kΩ isolation resistor so that it is asserted when the system reset signal ($\overline{\text{HRESET}}$) is asserted, ensuring that the JTAG scan chain is initialized during the power-on reset flow. Freescale recommends that the COP header be designed into the system as shown in Figure 78. If this is not possible, the isolation resistor will allow future access to $\overline{\text{TRST}}$ in case a JTAG interface may need to be wired onto the system in future debug situations.
- No pull-up/pull-down is required for TDI, TMS, or TDO.